## **Stanford Counter Correction Table** (12-Jan-2009)

STATION	Name	PAD ID	Target- board- range	LEO specific	LAGEOS- specific	ETALON- specific	Start year-doy	Stop year-doy
			dependent (mm)	(mm)	(mm)	(mm)	(yymmdd at 00:00)	(yymmdd at 00:00)
BEIL	Beijing	7249	+12	+10	+10	+9	2001 020 (010120)	-
BORL	Borowiec	7811	+9	0	0	+9	2002 127 (020507)	-
BREF	Brest	7604	+10	+10	+10	+9	2001 182 (010701)	-
GLSV	Kiev	1824	+6	+10	+10	+9	1999 314 (991110)	-
HELW	Helwan	7831	0	+10	+10	+9	1999 135 (990515)	-
KTZL	Katzively	1893	0	+10	+10	+9	1998 171 (980620)	-
KUNL	Kunming	7820	+9	+10	+10	+9	1998 140 (980520)	-
POT3	Potsdam	7841	0	+5	+5	+5	2001 201 (010720)	2004 050 (040219)
POTL	Potsdam	7836	0	+10	+10	+9	1992 129 (920508)	-
SFEL	San Fernando	7824	0	+8	+8	+8	2001 222 (010810)	-
SISL	Simosato	7838	+1	+10	+10	+9	2004 183 (040701)	-
SJUL	San Juan	7406	0	+10	+10	+9	2006 020 (060120)	-
WUHL	Wuhan	7231	0	+10	+10	+9	1999 001 (990101)	-
GRSL	Grasse	7835	+1	+10	+10	+9	1995 244 (950901)	-

The Table above gives estimates of corrections in mm to be added to one-way range measurements from each station for the time period shown. The correction to be added to a given satellite range observation is the sum of the **target-board-range dependent** correction and that given for the **specific satellite distance** broadly characterized for LEO, LAGEOS and ETALON heights.

The stations and data given in **bold** refer to estimates of Stanford counter errors that have been determined using high-precision linear event timers for calibration at the Space Geodesy Facility, Herstmonceux. Results for the other stations have been estimated from the known characteristics of Stanford counters, along with knowledge of calibration-board distances and calibration values reported in the site logs and in the stations' ILRS data.

These results should be taken as **estimates only** of the probable range errors for each station; the complex error-functions of the counters impose 2-3mm periodic errors, the exact magnitudes of which vary according to individual installation details, including cable lengths, etc., which will not be re-created on the test bench even when measurements have been carried out on the actual devices.